

EFS-Web Receipt date: 09/21/2005

JC20 Rec'd PCT/PTO 21 SEP 2005

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FORM PTO-1449 U.S. Department of Commerce Patent and Trademark Office List of Documents Cited by Applicant				Attorney Docket No. 297/171 PCT/US		Serial No. <b>10/550040</b>	
				Applicant(s): Johnson et al.			
				Filing Date: Herewith		Group	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing date if Appropriate
	1.	6,709,929	03/23/2004	Zhang et al.			
	2.	6,593,065	07/15/2003	Scherer			
	3.	6,214,246	04/10/2001	Craighead			
	4.	5,151,757	09/29/1992	Enoki et al.			
	5.	5,838,030	11/17/1998	Liu et al.			
	6.	6,242,293	06/05/2001	Danzilio			
	7.	6,008,509	12/28/1999	Inai et al.			
	8.	6,309,580	10/30/2001	Chou			
	9.	6,566,704	05/20/2003	Choi et al.			
	10.	6,593,065	07/15/2003	Scherer			
	11.	6,755,984	06/29/2004	Lee et al.			

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /B.K./

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## FOREIGN PATENT DOCUMENTS

10/550040

Examiner Initials	Cite No.	Document Number (country code, no., kind code (if known))	Publication Date	Name of Patentee or Applicant	Pages, columns, lines where relevant passages appear	T
	12.	JP 2004-034270	02/05/2004	II et al.		
	13.	JP 2003-073859	03/12/2003	Wada et al.		
	14.	JP 2003-045325	02/14/2003	Hatai et al.		
	15.	EP 1319948 A2	06/18/2003	Dong		

## OTHER DOCUMENTS

Examiner Initials	Cite No.	Include Author (in CAPITAL LETTERS), Title, Journal, Date, Pertinent Pages, Etc.	T
	16.	Commonly-assigned, co-pending U.S. Patent Application entitled, "Methods for Nanoscale Structures from Optical Lithography and Subsequent Lateral Growth," (Serial No. not yet assigned) (filed September 21, 2005).	
	17.	International Search Report and Written Opinion in PCT Application No. PCT/US04/08724 (November 19, 2004).	
	18.	International Preliminary Report on Patentability in PCT Application No. PCT/US04/08724 (May 31, 2005).	
	19.	International Search Report in PCT Application No. PCT/US04/08725 (February 28, 2005)	

EXAMINER /Brook Kebede/ DATE CONSIDERED 05/02/2008

\*Examiner Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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